

**SUPER-SEMI** 



# **SUPER-MOSFET**

Super Junction Metal Oxide Semiconductor Field Effect Transistor

800V Super Junction Power MOSFET SS\*80R850S

Rev. 1.5 Oct. 2019

www.supersemi.com.cn



September, 2013

SJ-FET

# SSF80R850S/SSP80R850S/SST80R850S/SSU80R850S 800V N-Channel MOSFET

### **Description**

SSMOS-FET is new generation of high voltage MOSFET family that is utilizing an advanced charge balance mechanism for outstanding low on-resistance and lower gate charge performance.

This advanced technology has been tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate and higher avalanche energy.

SJ-FET is suitable for various AC/DC power conversion in switching mode operation for higher efficiency.

#### **Features**

- Multi-Epi process SJ-FET
- 850V @TJ = 150 ℃
- Typ. RDS(on) = 0.8Ω ( TO-220F ) • Ultra Low Gate Charge (typ. Qg = 9.5nC)
- 100% avalanche tested



### **Absolute Maximum Ratings**

Symbol	Parameter		SSP_T_U80R850S	SSF80R850S	Unit
$V_{DSS}$	Drain-Source Voltage		800		V
I <sub>D</sub>	Drain Current -Continuous (TC = 25°C) -Continuous (TC = 100°C)		6.6* 4.2*		Α
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	20*		Α
$V_{GSS}$	Gate-Source voltage		±30		V
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)		86		mJ
I <sub>AR</sub>	Avalanche Current (Note 1)		1.7		Α
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1)		0.2		mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		15		V/ns
dVds/dt	Drain Source voltage slope (Vds=640V)		50		V/ns
P <sub>D</sub>	Power Dissipation (TC = 25°C)		63	28	W
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150		°C
TL	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds		300		°C

 $<sup>^{\</sup>star}$  Drain current limited by maximum junction temperature. Maximum duty cycle D=0.75.

#### **Thermal Characteristics**

Symbol	Parameter	SSP_T_U80R850S	SSF80R850S	Unit
R <sub>eJC</sub>	Thermal Resistance, Junction-to-Case	2.0	4.5	°C/W
R <sub>ecs</sub>	Thermal Resistance, Case-to-Sink Typ.	0.5	-	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62	80	°C/W



# Electrical Characteristics TC = 25°C unless otherwise noted

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Off Characteris	stics					
BVDSS	Drain-Source Breakdown Voltage	VGS = 0V, ID = 250µA, TJ = 25°C	800	-	-	V
		VGS = 0V, ID = 250μA, TJ = 150°C	-	850	-	V
ΔBVDSS/ΔTJ	Breakdown Voltage Temperature Coefficient	ID = 250µA, Referenced to 25°C	-	0.6	-	V/°C
IDSS	Zero Gate Voltage Drain Current	VDS = 800V, VGS = 0V -TJ = 150°C	-	- 10	1 -	μA μA
IGSSF	Gate-Body Leakage Current, Forward	VGS = 30V, VDS = 0V	-	-	100	nA
IGSSR	Gate-Body Leakage Current, Reverse	VGS = -30V, VDS = 0V	-	-	-100	nA
On Characteris	itics					
VGS(th)	Gate Threshold Voltage	VDS = VGS, ID = 250µA	2.5	3.5	4.5	V
RDS(on)	Static Drain-Source On-Resistance	VGS = 10V, ID = 3.5A (TO-220F/TO-220)	-	0.8	0.9	Ω
TCD3(011)	Static Brain-Source On-Resistance	VGS = 10V, ID = 3.5A (TO-251/TO-252)	-	0.85	0.93	Ω
gFS	Forward Transconductance	VDS = 40V, ID = 7A	-	6	-	S
Dynamic Chara	acteristics					
Ciss	Input Capacitance	VDS = 25V, VGS = 0V,	-	380	-	pF
Coss	Output Capacitance	f = 1MHz	-	115	-	pF
Crss	Reverse Transfer Capacitance		-	9	-	pF
Switching Char	racteristics					
td(on)	Turn-On Delay Time	VDD = 400V, ID = 3.5A, RG =	-	23	-	ns
tr	Turn-On Rise Time	25Ω(Note 4)	-	19	-	ns
td(off)	Turn-Off Delay Time		-	44	1	ns
tf	Turn-Off Fall Time		-	18	1	ns
Qg	Total Gate Charge	VDS = 450V, ID = 3.5A, VGS =	-	9.5	-	nC
Qgs	Gate-Source Charge	10V (Note 4)	-	1.9	-	nC
Qgd	Gate-Drain Charge		-	4.5	-	nC
Drain-Source D	Diode Characteristics and Maximum Rating	s				
Is	Maximum Continuous Drain-Source Di	ode Forward Current	-	-	7	Α
Ism	Maximum Pulsed Drain-Source Diode	ximum Pulsed Drain-Source Diode Forward Current		_	20	Α
VsD	Drain-Source Diode Forward Voltage	Vgs = 0V, Is = 7A	-	0.9	1.5	V
trr	Reverse Recovery Time	V <sub>R</sub> = 400V, VGS = 0V, IF = 7A, dIF/dt =100A/μs	-	550	-	ns
Qrr	Reverse Recovery Charge	ir = /A, αir/αι = 100A/μS	-	4.8	-	μC
I <sub>rrm</sub>	Peak reverse recovery Current		-	15.5	-	Α

### NOTES:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature 2.  $I_{AS}\!=\!1.7A$  , VDD=50V, Starting TJ=25  $^{\circ}\text{C}$

- $2.1_{AS}$  Th.  $1_{AS}$  Th. 1



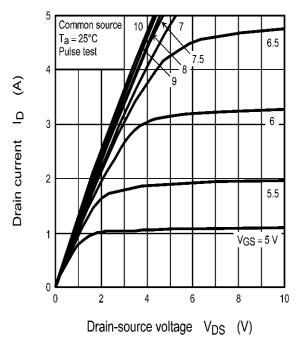


Figure 1: On-Region Characteristics@25°C

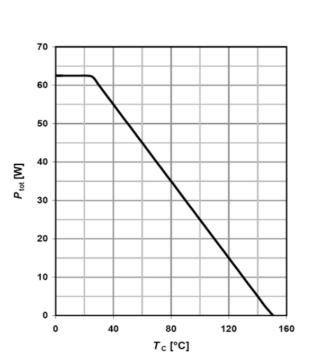


Figure 3:Power Dissipation TO-220, TO-252, TO-251

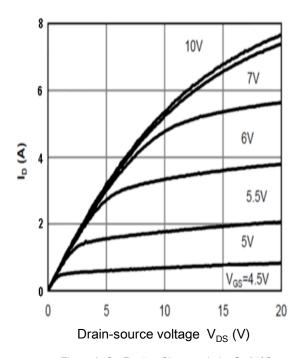


Figure 2: On-Region Characteristics@125°C

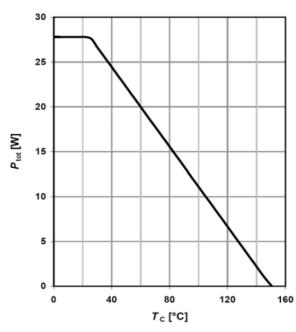


Figure 4: Power dissipation TO-220FullPAK



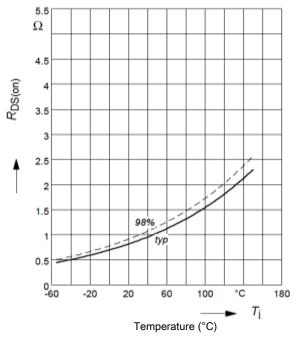


Figure 5: On-Resistance vs. Junction Temperature

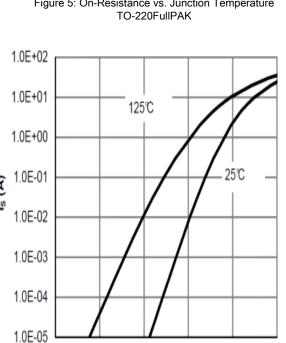


Figure 7: Body-Diode Characteristics

0.4 V<sub>SD</sub> (V)

0.6

8.0

1.0

0.2

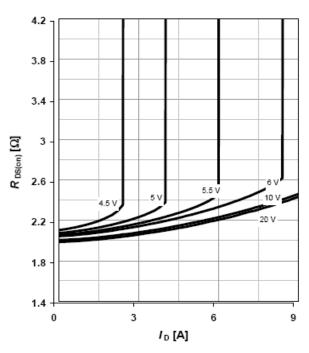


Figure 6: On-Resistance vs. Drain Current, Tj=150°C

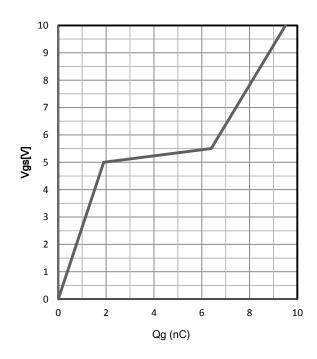
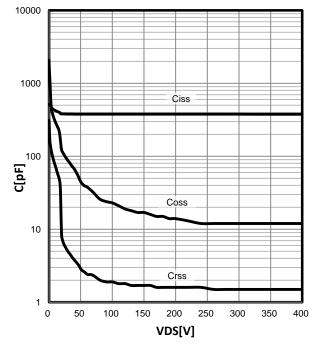


Figure 8: Gate-Charge Characteristics

0.0





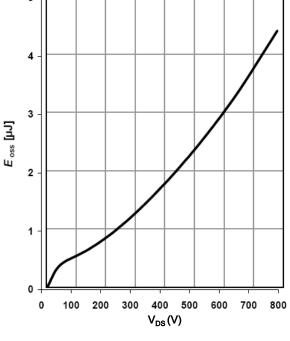
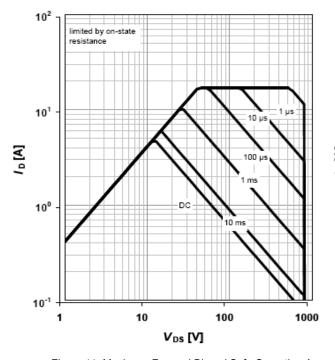
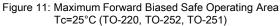


Figure 9: Capacitance Characteristics

Figure 10: Coss stored Energy





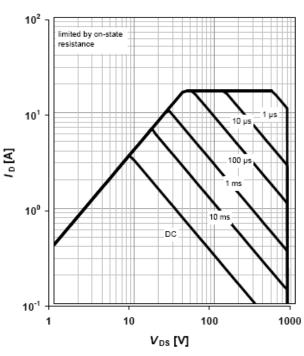


Figure 12: Maximum Forward Biased Safe Operating Area Tc=25°C (TO-220 FullPAK)



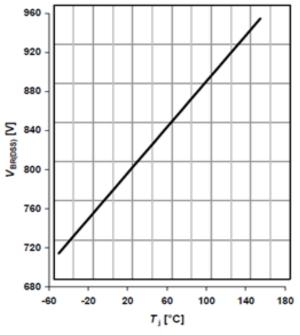
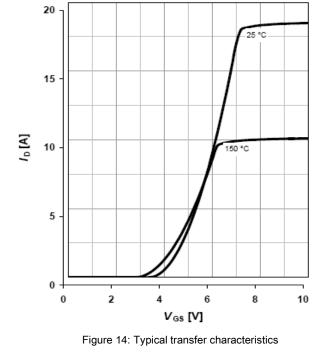


Figure 13: Break Down vs. Junction Temperature



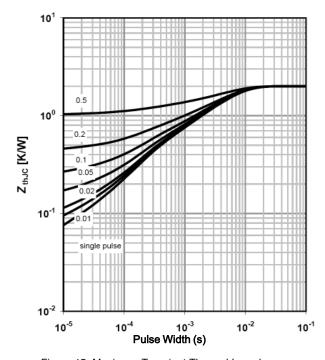


Figure 15: Maximum Transient Thermal Impedance TO-220, TO-252, TO-251

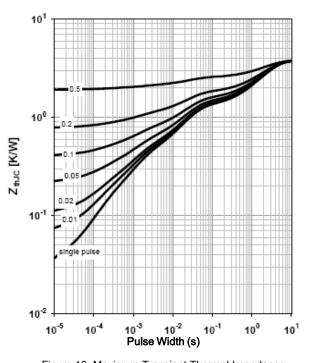


Figure 16: Maximum Transient Thermal Impedance TO-220 FULLPAK



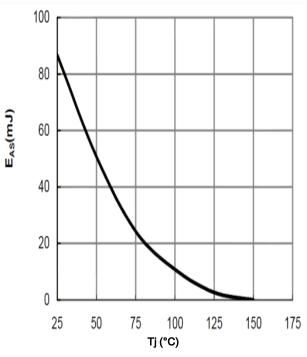
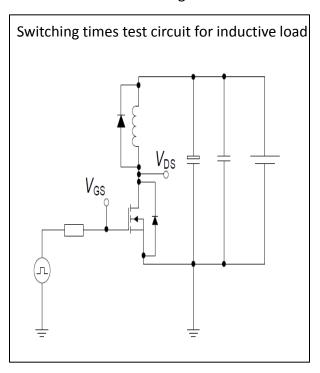


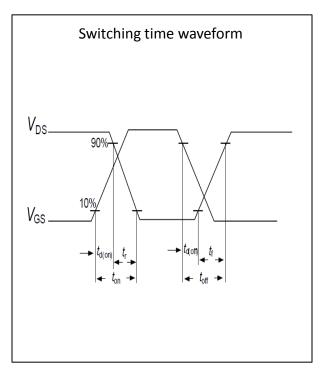
Figure 17: Avalanche energy



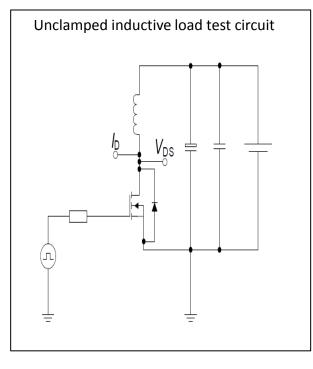
### **Test circuits**

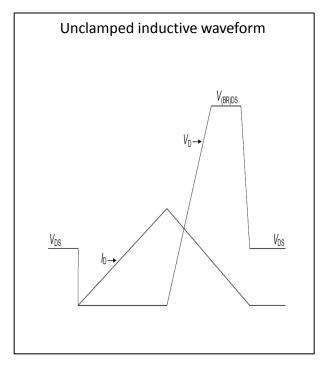
Switching times test circuit and waveform for inductive load





### Unclamped inductive load test circuit and waveform

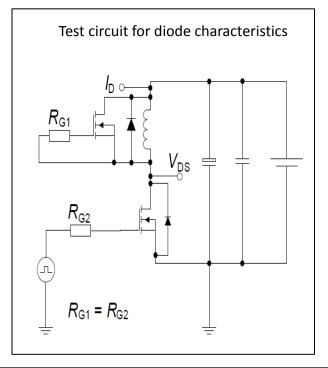


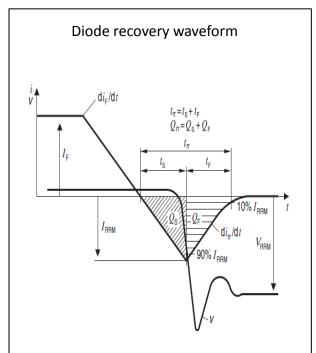


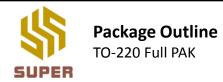


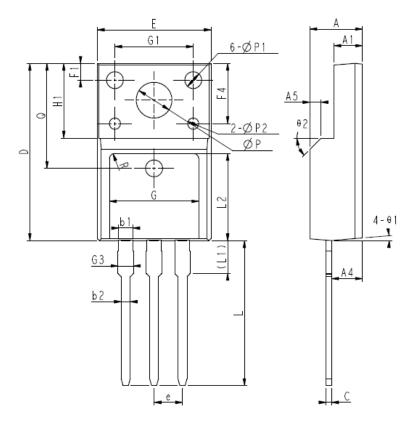
## **Test circuits**

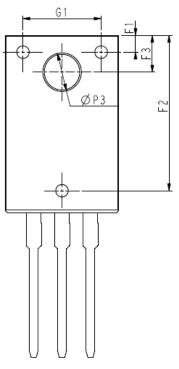
Test circuit and waveform for diode characteristics

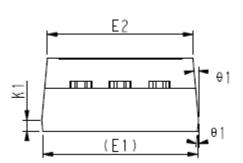












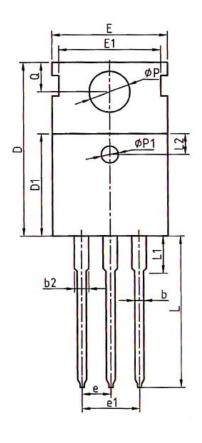
### COMMON DIMENSIONS

SYMBOL	MM		
SYMBOL	MIN	NOM	MAX
E	10.00	10.16	10.32
E1	9.94	10.04	10.14
E2	9.36	9.46	9.56
A	4.50	4.70	4.90
A1	2.34	2.54	2.74
A4	2.66	2.76	2.86
A5		1.00REF	
с	0.45	0.50	0.60
D	15.67	15.87	16.07
Q		9. 40REF	
H1		6.70REF	
e		2.54BSC	
ФΡ		3. 18REF	
L	12.78	12.98	13.18
L1	2.83	2. 93	3. 03
L2	7.70	7.80	7. 90
ФР1	1.40	1.50	1.60
ФР2	0.95	1.00	1.05
ФР3		3. 45REF	
θ 1	3°	5°	7°
θ2	-	45°	-
F1	1.00	1.50	2.00
F2	13.80	13.90	14.00
F3	3.20	3. 30	3. 40
F4	5.30	5. 40	5. 50
G	7.80	8.00	8.20
G1	6.90	7.00	7.10
G3	1.25	1.35	1.45
b1	1.23	1.28	1.38
b2	0.75	0.80	0.90
K1	0.65	0.70	0.75
R		0.50REF	

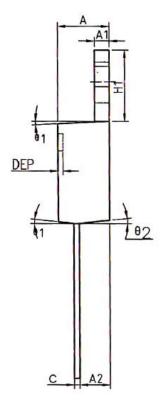


# **Package Outline**

TO-220







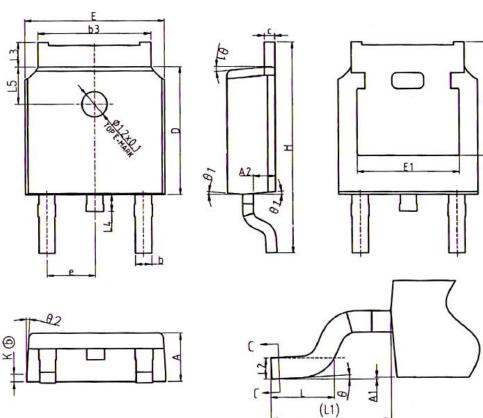
#### **COMMON DIMENIONS**

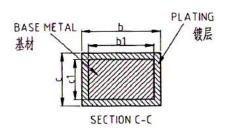
SYMBOL	2	3		
2 IMBUL	MIN	NDM	MAX	
Α	4.40	4.57	4.70	
A1	1.27	1.30	1.37	
A2	2.35	2.40	2.50	
ь	0.77	0.80	0.90	
b2	1.17	1.27	1.36	
С	0.48	0.50	0.56	
D	15.40	15.60	15.80	
D1	9.00	9.10	9.20	
DEP	0.05	0.10	0.20	
Ε	9.80	10.00	10.20	
E1	-	8.70	-	
E2	9.80	10.00	10.20	
ØP1	1.40	1.50	1.60	
е	2.54BSC			
e1	5.08BSC			
H1	6.40	6.50	6.60	
L	12.75	13.50	13.65	
L1	-	3.10	3.30	
L2		2.50REF		
ΦP	3.50	3.60	3.63	
q	2.73	2.80	2.87	
θ1	5	7	9.	
θ2	1"	3	5	
θ3	1'	3"	5'	



# Package Outline

TO-252



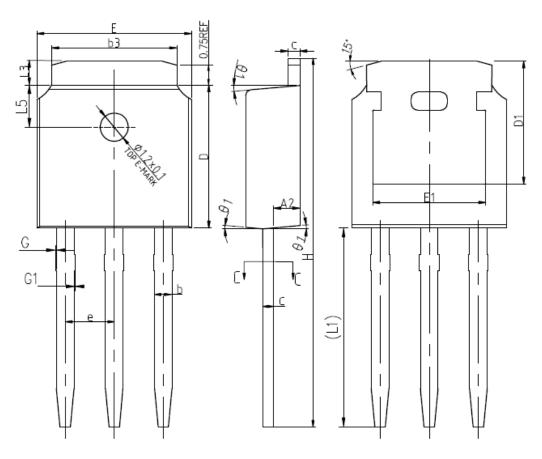


COMMON DIMENSIONS				
SYMBOL	MM			
SYMBOL	MIN	NOM	MAX	
A	2.20	2.30	2.38	
A1	0.00	-	0.10	
A2	0.97	1.07	1.17	
b	0.72	0.78	0.85	
b1	0.71	0.76	0.81	
b3	5.23	5.33	5.46	
c	0.47	0.53	0.58	
c1	0.46	0.51	0.56	
D	6.00	6.10	6.20	
D1		5.30REF		
E	6.50	6.60	6.70	
E1	4.70	4.83	4.92	
e		2.286BSC	,	
H	9.90	10.10	10.30	
L	1.40	1.50	1.70	
L1		2.90REF		
L2		0.51BSC		
L3	0.90	-	1.25	
L4	0.60	0.80	1.00	
L5	1.70	1.80	1.90	
θ	0°	-	8°	
θ1	5°	7°	9°	
θ2	5°	<i>7</i> °	9°	
K	0.40REF			

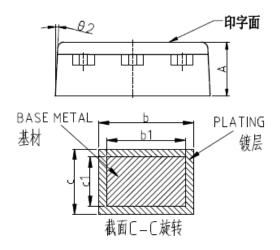


# Package Outline

TO-251



COMMON DIMENSIONS



CAMBOL	MM			
SYMBOL	MIN	NOM	MAX	
A	2. 20	2. 30	2. 38	
A2	0. 97	1.07	1. 17	
Ъ	0.72	0.78	0.85	
b1	0.71	0.76	0.81	
b3	5. 23	5. 33	5. 46	
С	0.47	0. 53	0.58	
c1	0.46	0. 51	0.56	
D	6. 00	6. 10	6. 20	
D1		5. 30REF		
E	6. 50	6.60	6. 70	
E1	4. 70	4.83	4. 92	
e		2. 286BSC		
Н	16. 10	16.40	16.60	
L1	9. 20	9. 40	9.60	
L3	0. 90	1.02	1.25	
L5	1. 70	1.80	1.90	
θ 1	5°	7°	9°	
θ2	5°	7°	9°	



### **DISCLAIMER**

SUPER SEMICONDUCTOR reserves the right to make changes WITHOUT further notice to any products herein to improve reliability, function, or design.

For documents and material available from this datasheet, SUPER SEMICONDUCTOR does not warrant or assume any legal liability or responsibility for the accuracy, completeness of any product or technology disclosed hereunder.

The information given in this document shall in no event be regarded as a guarantee of conditions or characteristics. With respect to any examples or hints given herein, any typical values stated herein and/or any information regarding the application of the device, SUPER SEMICONDUCTOR hereby disclaims any and all warranties and liabilities of any kind, including without limitation, warranties of non-infringement of intellectual property rights of any third party.

The products shown herein are not designed for use as critical components in medical, life-saving, or life-sustaining applications, whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness. Customers using or selling SUPER SEMICONDUCTOR products not expressly indicated for use in such applications do so entirely at their own risk and agree to fully indemnify SUPER SEMICONDUCTOR for any damages arising or resulting from such use or sale.

#### INFORMATION

For further information on technology, delivery terms and conditions and prices, please contact SUPER SEMICONDUCTOR office or website (www.supersemi.com.cn).